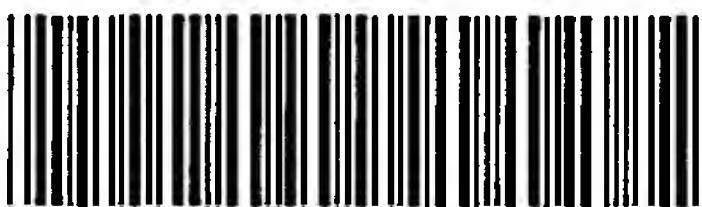


## **Search Notes**



**Application/Control No.**

10/651 663

**Examiner**

Yuwen Pan

**Applicant(s)/Patent under  
Reexamination**

XIE, FEI

## Art Unit

2682

SEARCHED

# SEARCH NOTES (INCLUDING SEARCH STRATEGY)

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner